## Notice of References Cited

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				U.S. PATENT DOCUMENTS	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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## FOREIGN PATENT DOCUMENTS

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## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Sorlie et al (PNAS, September 2001, 98(19):10869-10874)
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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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